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(54) Title: METHOD AND SYSTEM FOR CHILLER PERFORMANCE ANOMALY DIAGNOSIS

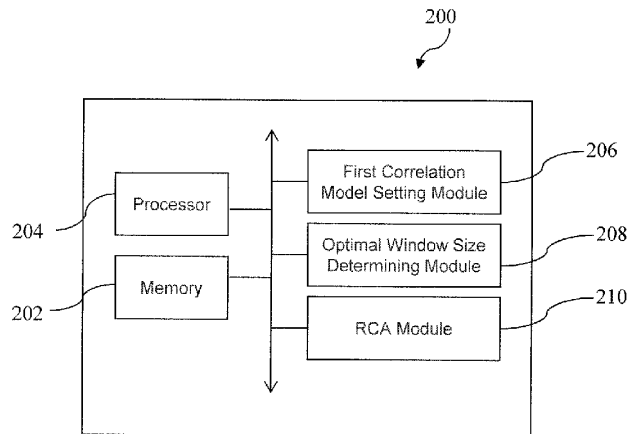


FIG. 2

(57) Abstract: There is provided a computer-implemented method for chiller performance anomaly diagnosis. The method includes: setting a first correlation model between a performance parameter of a chiller and a first plurality of operational parameters; determining an optimal window size for performing a root cause analysis diagnosis based on the first correlation model with respect to an anomaly identified in the performance parameter; and performing the root cause analysis diagnosis based on the first correlation model and the optimal window size with respect to the anomaly for determining a root cause of the anomaly identified in the performance parameter of the chiller, the root cause analysis diagnosis being performed on a dataset comprising measurement data relating to the performance parameter and the first plurality of operational parameters collected over a period of time, including anomaly measurement data having an anomaly period associated with the anomaly.

